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|-----------------------------------|--|-------------------------|---|-------------|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination | |
| | | 10/711,134 | INOUE ET AL. | |
| Examiner | | Art Unit | 2826 | Page 1 of 1 |
| Fazli Erdem | | | | |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| | A | US-6,429,467 | 08-2002 | Ando, Yuji | 257/194 |
| | B | US-6,483,135 | 11-2002 | Mizuta et al. | 257/283 |
| | C | US-6,274,889 | 08-2001 | Ota et al. | 257/77 |
| | D | US-5,374,835 | 12-1994 | Shimada et al. | 257/284 |
| | E | US-6,316,793 | 11-2001 | Sheppard et al. | 257/103 |
| | F | US-6,064,082 | 05-2000 | Kawai et al. | 257/192 |
| | G | US-5,399,886 | 03-1995 | Hasegawa, Yuichi | 257/192 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| | | |
|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

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